

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/799,647	WYETH, MARTIN	
Examiner		Art Unit		Page 1 of 1
Milap Shah		3712		

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	U	English translation of JP 06-022319 A - includes abstract, claims, description of drawings and detailed description.
	V	English translation of JP 06-311474 A - includes abstract, claims, description of drawings and detailed description.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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